

# C3M0025065K

Silicon Carbide Power MOSFET  
C3M™ MOSFET Technology  
N-Channel Enhancement Mode

## Features

- C3M™ SiC MOSFET technology
- Optimized package with separate driver source pin
- 8mm of creepage distance between drain and source
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery ( $Q_{rr}$ )
- Halogen free, RoHS compliant

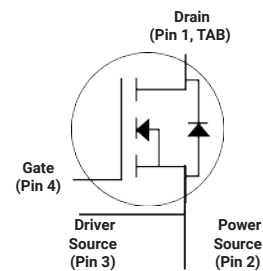
## Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

## Applications

- EV chargers
- UPS
- Solar inverters
- Industrial SMPS
- DC/DC converters

## Package



Part Number	Package	Marking
C3M0025065K	TO 247-4	C3M0025065K

## Maximum Ratings

Symbol	Parameter	Value	Unit	Note
$V_{DSS}$	Drain - Source Voltage, $T_c = 25^\circ\text{C}$	650	V	
$V_{GSmax}$	Gate - Source Voltage	-8/+19	V	Note: 1
$I_D$	Continuous Drain Current, $V_{GS} = 15\text{ V}$ , $T_c = 25^\circ\text{C}$	97	A	Fig. 19 Note: 2
	Continuous Drain Current, $V_{GS} = 15\text{ V}$ , $T_c = 100^\circ\text{C}$	70		
$I_{D(pulse)}$	Pulsed Drain Current, Pulse width $t_p$ limited by $T_{jmax}$	251	A	Fig. 22
$P_D$	Power Dissipation, $T_c=25^\circ\text{C}$ , $T_j = 175^\circ\text{C}$	326	W	Fig. 20 Note: 2
$T_J, T_{stg}$	Operating Junction and Storage Temperature	-40 to +175	$^\circ\text{C}$	
$T_L$	Solder Temperature, 1.6mm (0.063") from case for 10s	260	$^\circ\text{C}$	
$M_d$	Mounting Torque, (M3 or 6-32 screw)	1	Nm	
		8.8	lbf-in	

Note (1): Recommended turn off / turn on gate voltage  $V_{GS} = -4V...0V / +15V$

Note (2): Verified by design


**Electrical Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note	
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	650			V	$V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$		
$V_{GS(th)}$	Gate Threshold Voltage	1.8	2.3	3.6	V	$V_{DS} = V_{GS}, I_D = 9.22\ \text{mA}$	Fig. 11	
			1.9		V	$V_{DS} = V_{GS}, I_D = 9.22\ \text{mA}, T_J = 175^\circ\text{C}$		
$I_{DSS}$	Zero Gate Voltage Drain Current		1	50	$\mu\text{A}$	$V_{DS} = 650\ \text{V}, V_{GS} = 0\ \text{V}$		
$I_{GSS}$	Gate-Source Leakage Current		10	250	nA	$V_{GS} = 15\ \text{V}, V_{DS} = 0\ \text{V}$		
$R_{DS(on)}$	Drain-Source On-State Resistance		25	34	m $\Omega$	$V_{GS} = 15\ \text{V}, I_D = 33.5\ \text{A}$	Fig. 4, 5, 6	
			33			$V_{GS} = 15\ \text{V}, I_D = 33.5\ \text{A}, T_J = 175^\circ\text{C}$		
$g_{fs}$	Transconductance		25		S	$V_{DS} = 20\ \text{V}, I_{DS} = 33.5\ \text{A}$	Fig. 7	
			24			$V_{DS} = 20\ \text{V}, I_{DS} = 33.5\ \text{A}, T_J = 175^\circ\text{C}$		
$C_{iss}$	Input Capacitance		2980		pF	$V_{GS} = 0\ \text{V}, V_{DS} = 0\ \text{V to } 600\ \text{V}$ $F = 1\ \text{Mhz}$ $V_{AC} = 25\ \text{mV}$	Fig. 17, 18	
$C_{oss}$	Output Capacitance		178					
$C_{rss}$	Reverse Transfer Capacitance		12					
$C_{o(er)}$	Effective Output Capacitance (Energy Related)		236					Note: 3
$C_{o(tr)}$	Effective Output Capacitance (Time Related)		340					Note: 3
$E_{oss}$	$C_{oss}$ Stored Energy		37		$\mu\text{J}$	$V_{DS} = 600\ \text{V}, F = 1\ \text{Mhz}$	Fig. 16	
$E_{ON}$	Turn-On Switching Energy (Body Diode)		121		$\mu\text{J}$	$V_{DS} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}, I_D = 33.5\ \text{A},$ $R_{G(ext)} = 2.5\ \Omega, L = 59\ \mu\text{H}, T_J = 175^\circ\text{C}$ FWD = Internal Body Diode of MOSFET	Fig. 25	
$E_{OFF}$	Turn Off Switching Energy (Body Diode)		53					
$E_{ON}$	Turn-On Switching Energy (External Diode)		73		$\mu\text{J}$	$V_{DS} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}, I_D = 33.5\ \text{A},$ $R_{G(ext)} = 2.5\ \Omega, L = 59\ \mu\text{H}, T_J = 175^\circ\text{C}$ FWD = External SiC DIODE	Fig. 25	
$E_{OFF}$	Turn Off Switching Energy (External Diode)		82					
$t_{d(on)}$	Turn-On Delay Time		12		ns	$V_{DD} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}$ $I_D = 33.5\ \text{A}, R_{G(ext)} = 2.5\ \Omega$ Timing relative to $V_{DS}$ Inductive load	Fig. 26	
$t_r$	Rise Time		18					
$t_{d(off)}$	Turn-Off Delay Time		25					
$t_f$	Fall Time		8					
$R_{G(int)}$	Internal Gate Resistance		1.3		$\Omega$	$f = 1\ \text{MHz}, V_{AC} = 25\ \text{mV}$		
$Q_{gs}$	Gate to Source Charge		34		nC	$V_{DS} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}$ $I_D = 33.5\ \text{A}$ Per IEC60747-8-4 pg 21	Fig. 12	
$Q_{gd}$	Gate to Drain Charge		33					
$Q_g$	Total Gate Charge		112					

Note (3):  $C_{o(er)}$ , a lumped capacitance that gives same stored energy as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 400V  
 $C_{o(tr)}$ , a lumped capacitance that gives same charging time as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 400V


**Reverse Diode Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
$V_{SD}$	Diode Forward Voltage	5.0		V	$V_{GS} = -4\text{ V}, I_{SD} = 16.8\text{ A}, T_J = 25^\circ\text{C}$	Fig. 8, 9, 10
		4.5		V	$V_{GS} = -4\text{ V}, I_{SD} = 16.8\text{ A}, T_J = 175^\circ\text{C}$	
$I_S$	Continuous Diode Forward Current		52	A	$V_{GS} = -4\text{ V}, T_c = 25^\circ\text{C}$	
$I_{S,pulse}$	Diode pulse Current		251	A	$V_{GS} = -4\text{ V}$ , pulse width $t_p$ limited by $T_{jmax}$	
$t_{rr}$	Reverse Recover time	16		ns	$V_{GS} = -4\text{ V}, I_{SD} = 33.5\text{ A}, V_R = 400\text{ V}$ $dif/dt = 5560\text{ A}/\mu\text{s}, T_J = 175^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	453		nC		
$I_{rrm}$	Peak Reverse Recovery Current	54		A		
$t_{rr}$	Reverse Recover time	22		ns	$V_{GS} = -4\text{ V}, I_{SD} = 33.5\text{ A}, V_R = 400\text{ V}$ $dif/dt = 1575\text{ A}/\mu\text{s}, T_J = 175^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	293		nC		
$I_{rrm}$	Peak Reverse Recovery Current	22		A		

**Thermal Characteristics**

Symbol	Parameter	Typ.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	0.46	$^\circ\text{C}/\text{W}$		Fig. 21
$R_{\theta JA}$	Thermal Resistance From Junction to Ambient	40			



Typical Performance

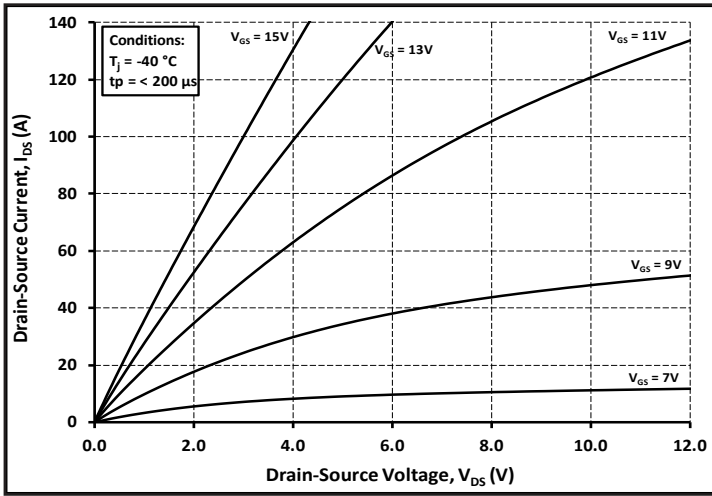


Figure 1. Output Characteristics  $T_J = -40\text{ }^\circ\text{C}$

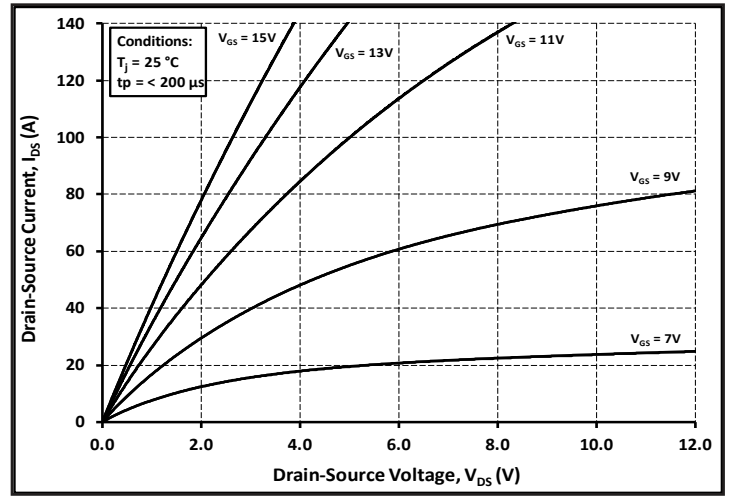


Figure 2. Output Characteristics  $T_J = 25\text{ }^\circ\text{C}$

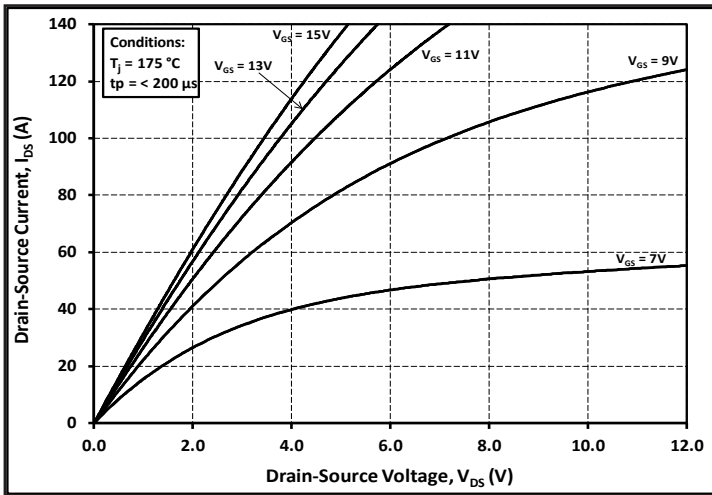


Figure 3. Output Characteristics  $T_J = 175\text{ }^\circ\text{C}$

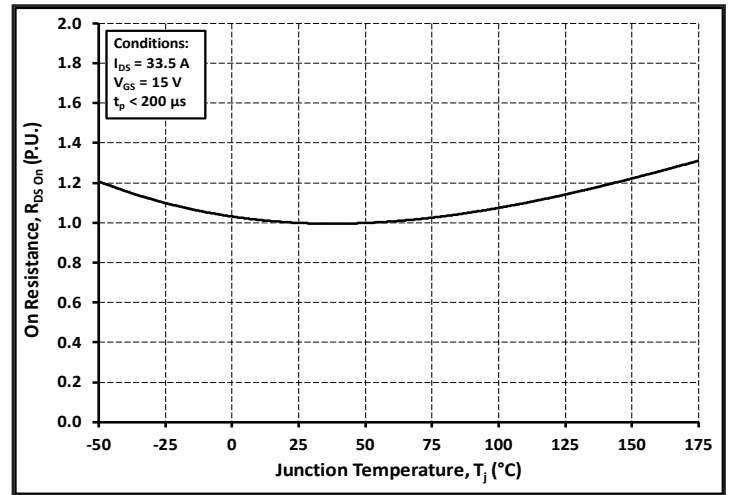


Figure 4. Normalized On-Resistance vs. Temperature

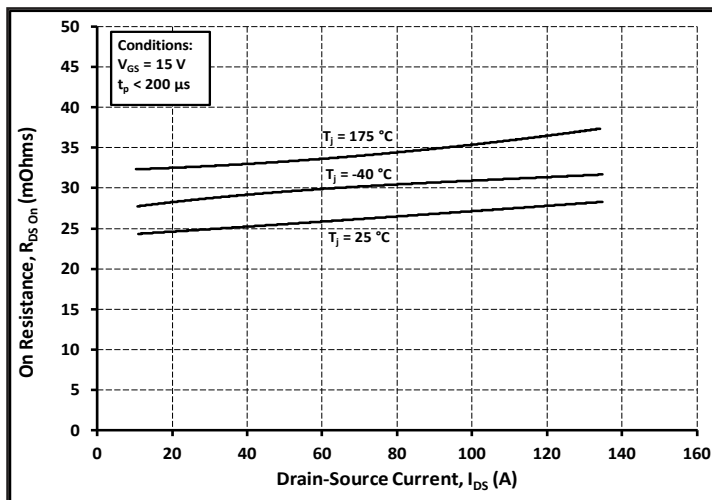


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

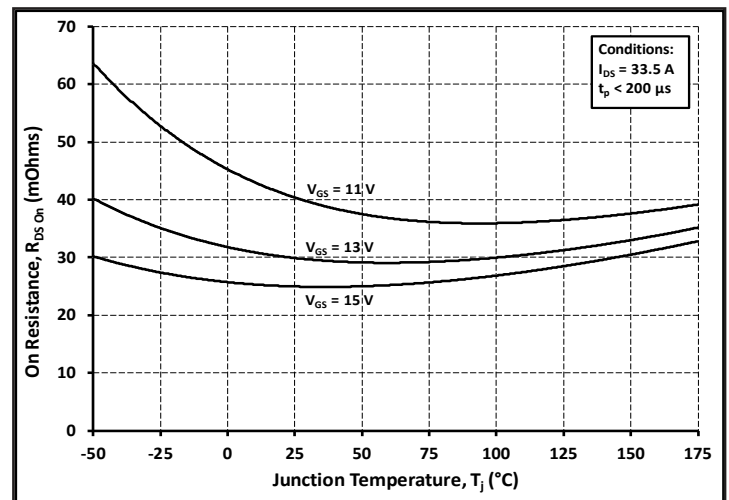


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

Typical Performance

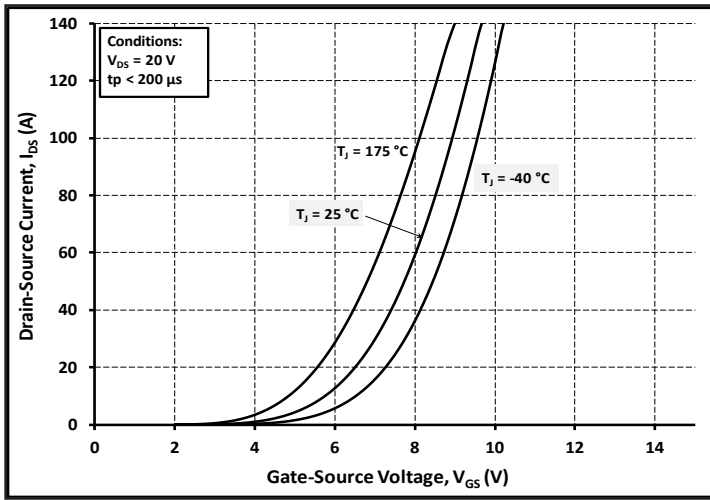


Figure 7. Transfer Characteristic for Various Junction Temperatures

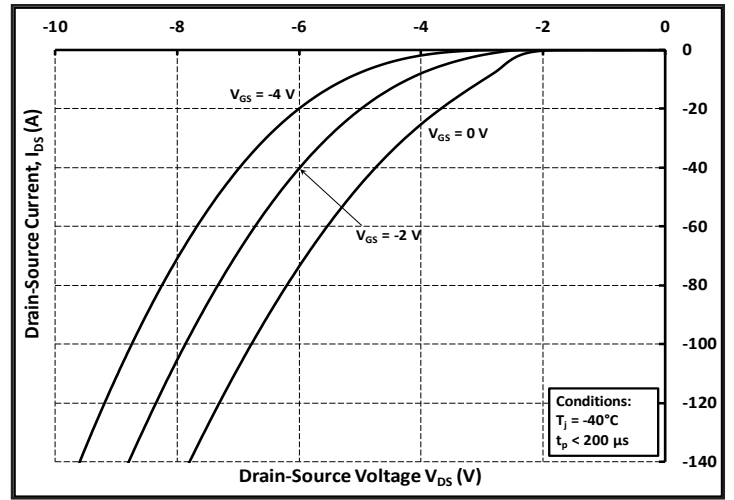


Figure 8. Body Diode Characteristic at -40 °C

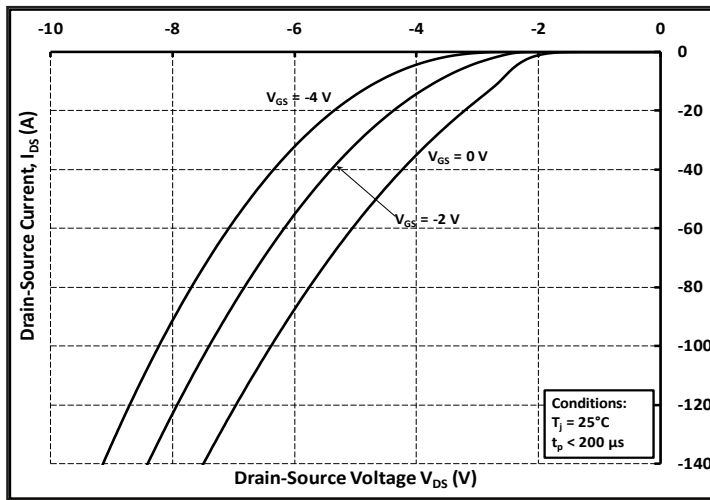


Figure 9. Body Diode Characteristic at 25 °C

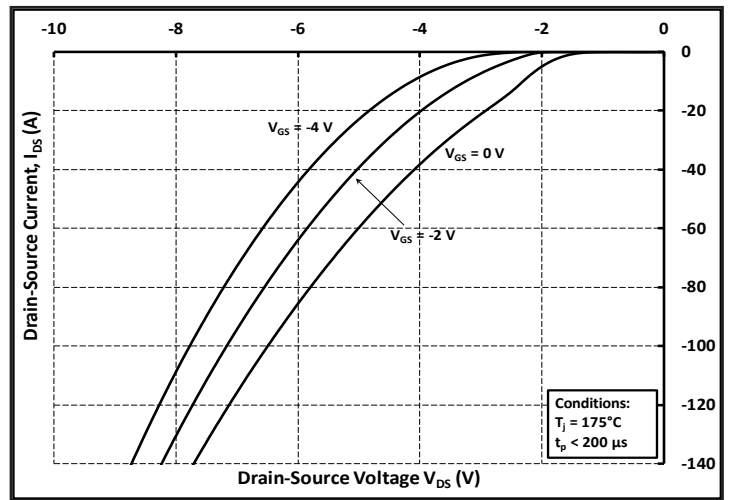


Figure 10. Body Diode Characteristic at 175 °C

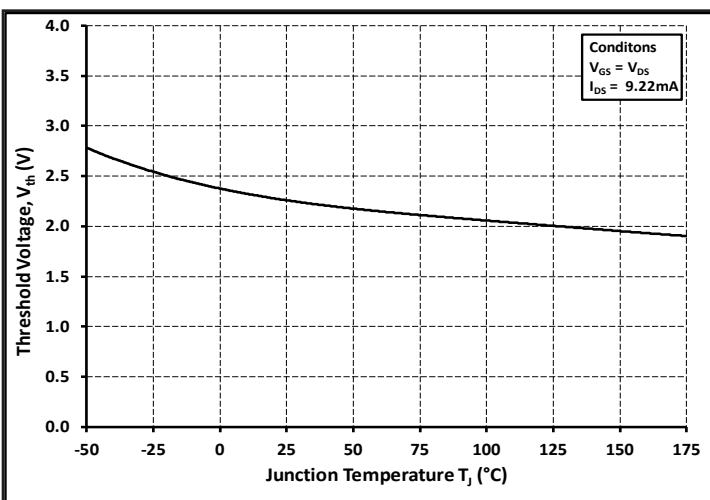


Figure 11. Threshold Voltage vs. Temperature

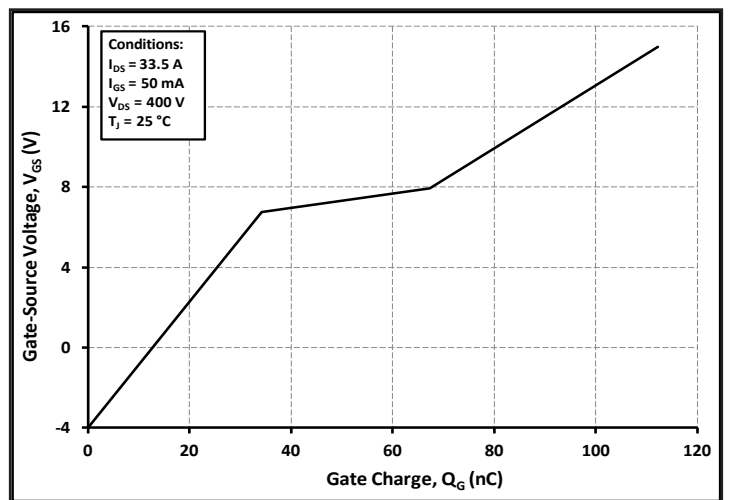


Figure 12. Gate Charge Characteristics

Typical Performance

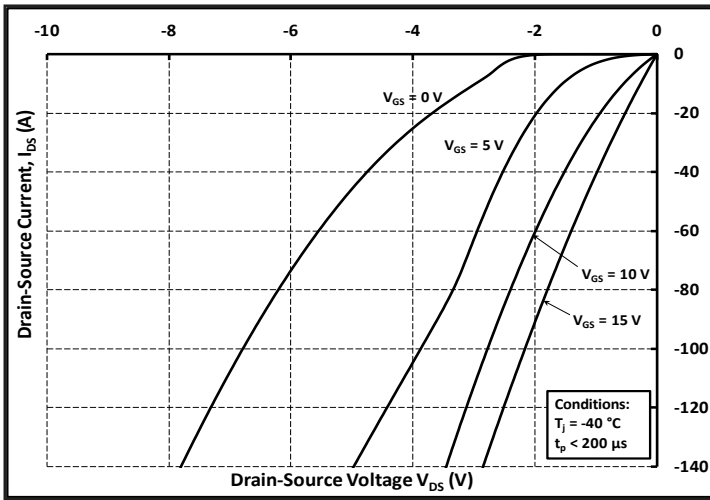


Figure 13. 3rd Quadrant Characteristic at -40 °C

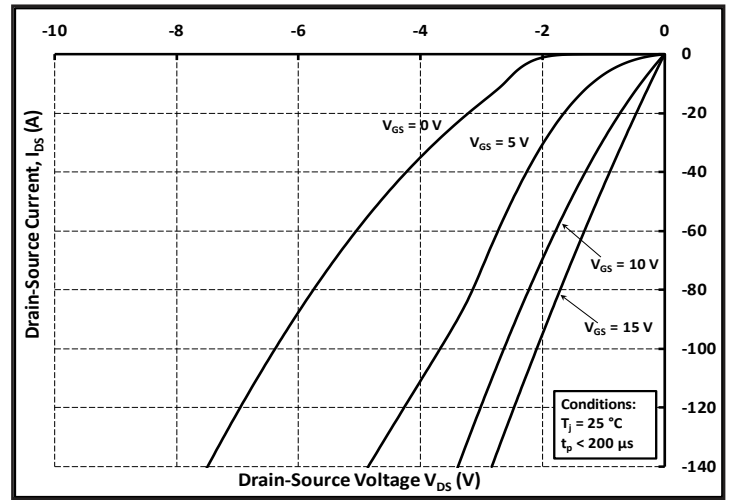


Figure 14. 3rd Quadrant Characteristic at 25 °C

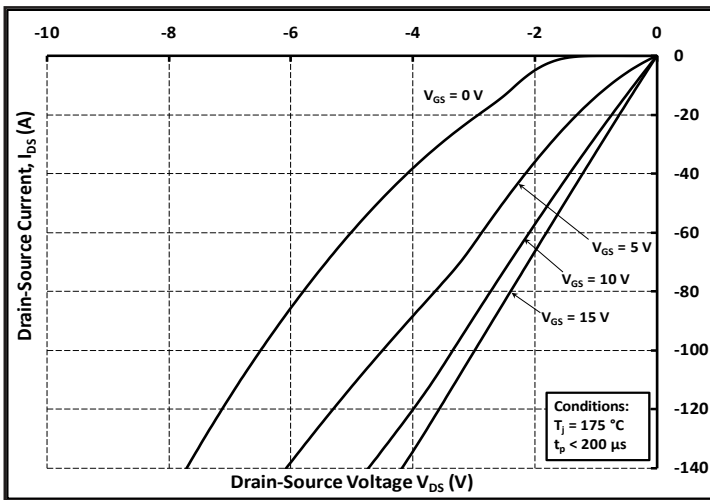


Figure 15. 3rd Quadrant Characteristic at 175 °C

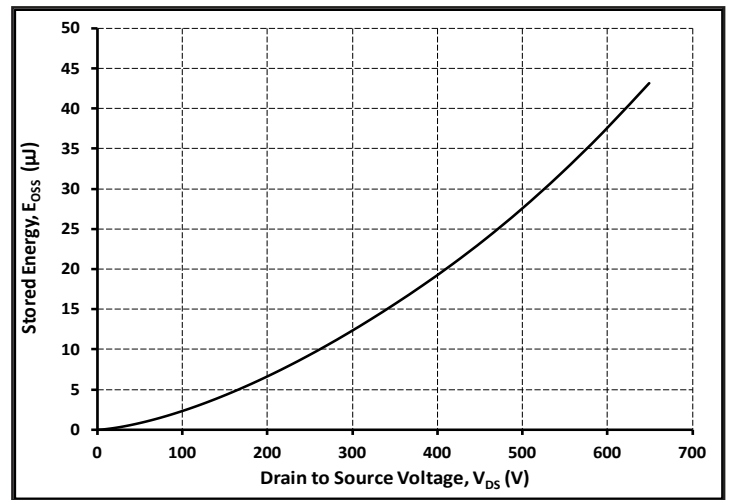


Figure 16. Output Capacitor Stored Energy

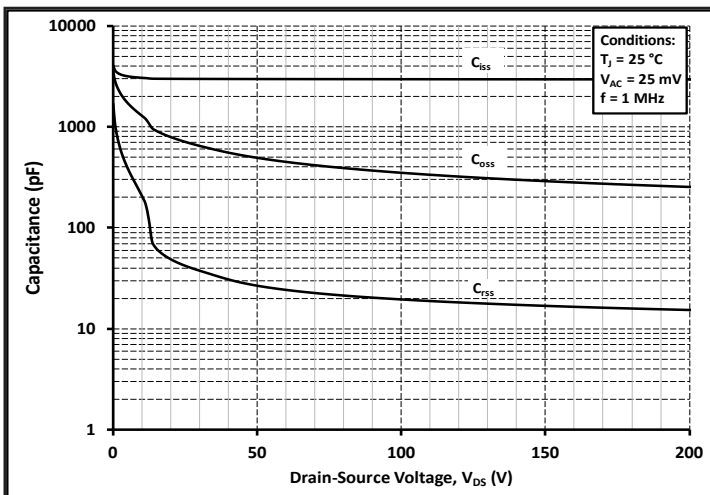


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

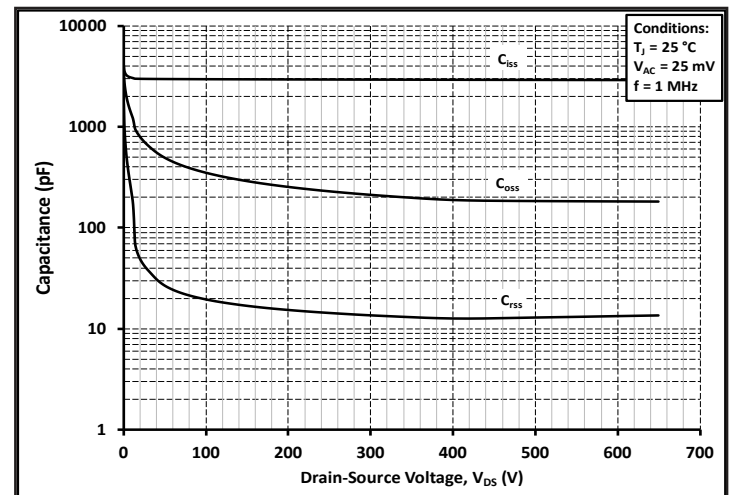


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 650V)

Typical Performance

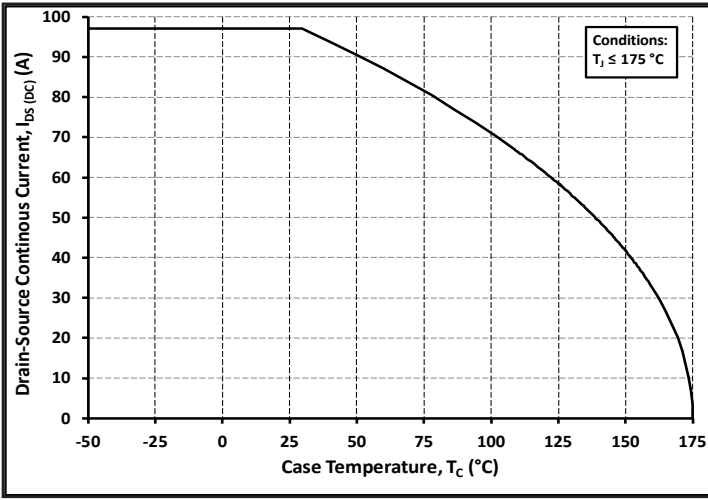


Figure 19. Continuous Drain Current Derating vs. Case Temperature

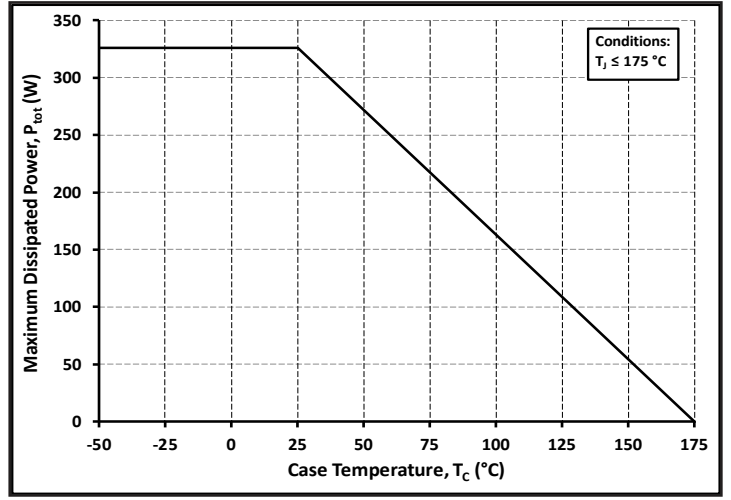


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

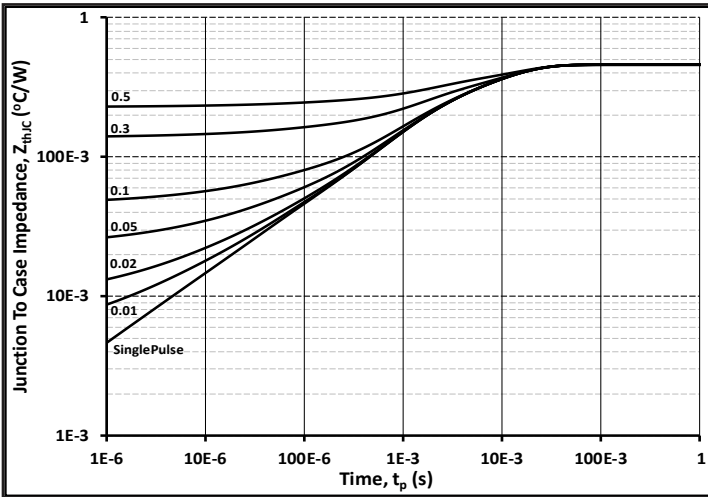


Figure 21. Transient Thermal Impedance (Junction - Case)

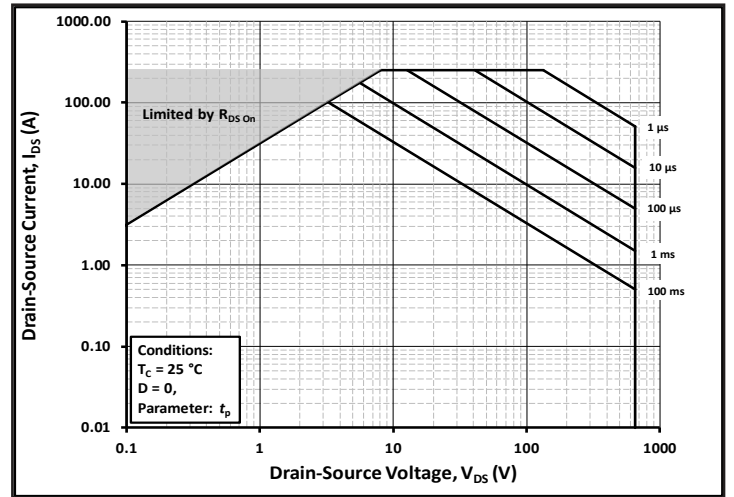


Figure 22. Safe Operating Area

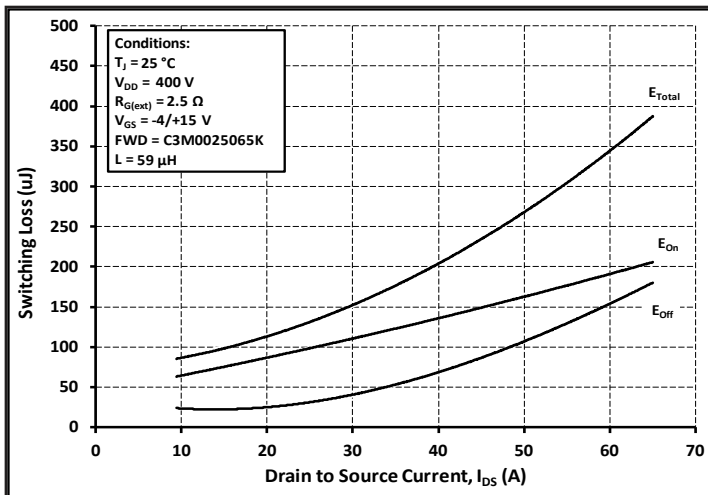


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 400V$ )

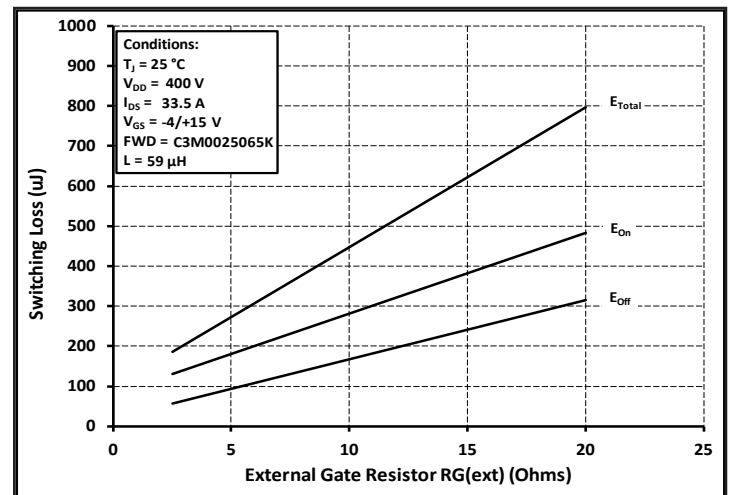


Figure 24. Clamped Inductive Switching Energy vs.  $R_{G(ext)}$



Typical Performance

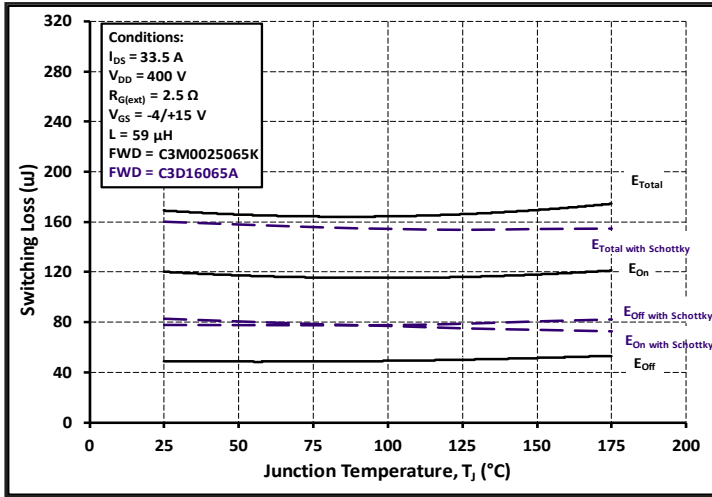


Figure 25. Clamped Inductive Switching Energy vs. Temperature

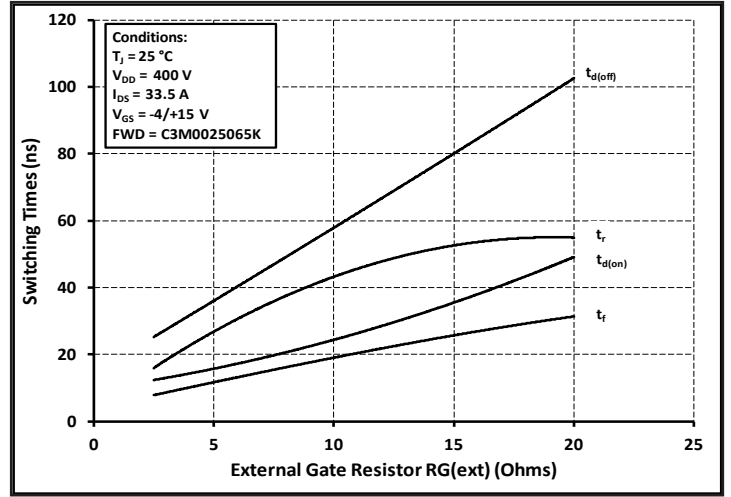


Figure 26. Switching Times vs.  $R_{G(ext)}$



Test Circuit Schematic

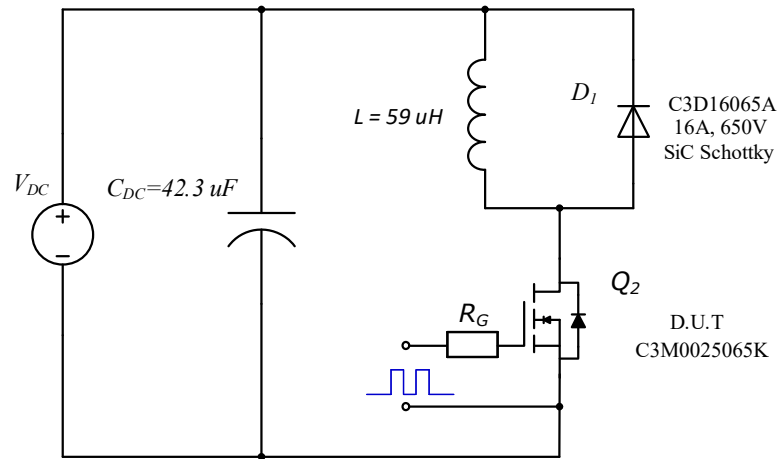


Figure 27. Clamped Inductive Switching Waveform Test Circuit

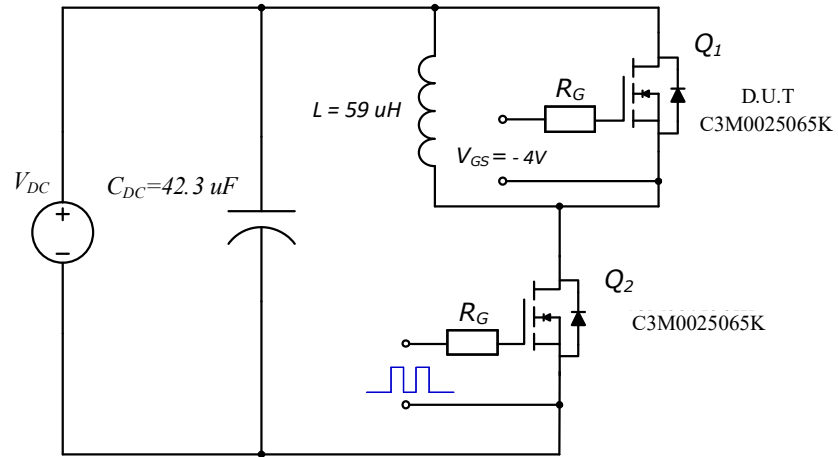
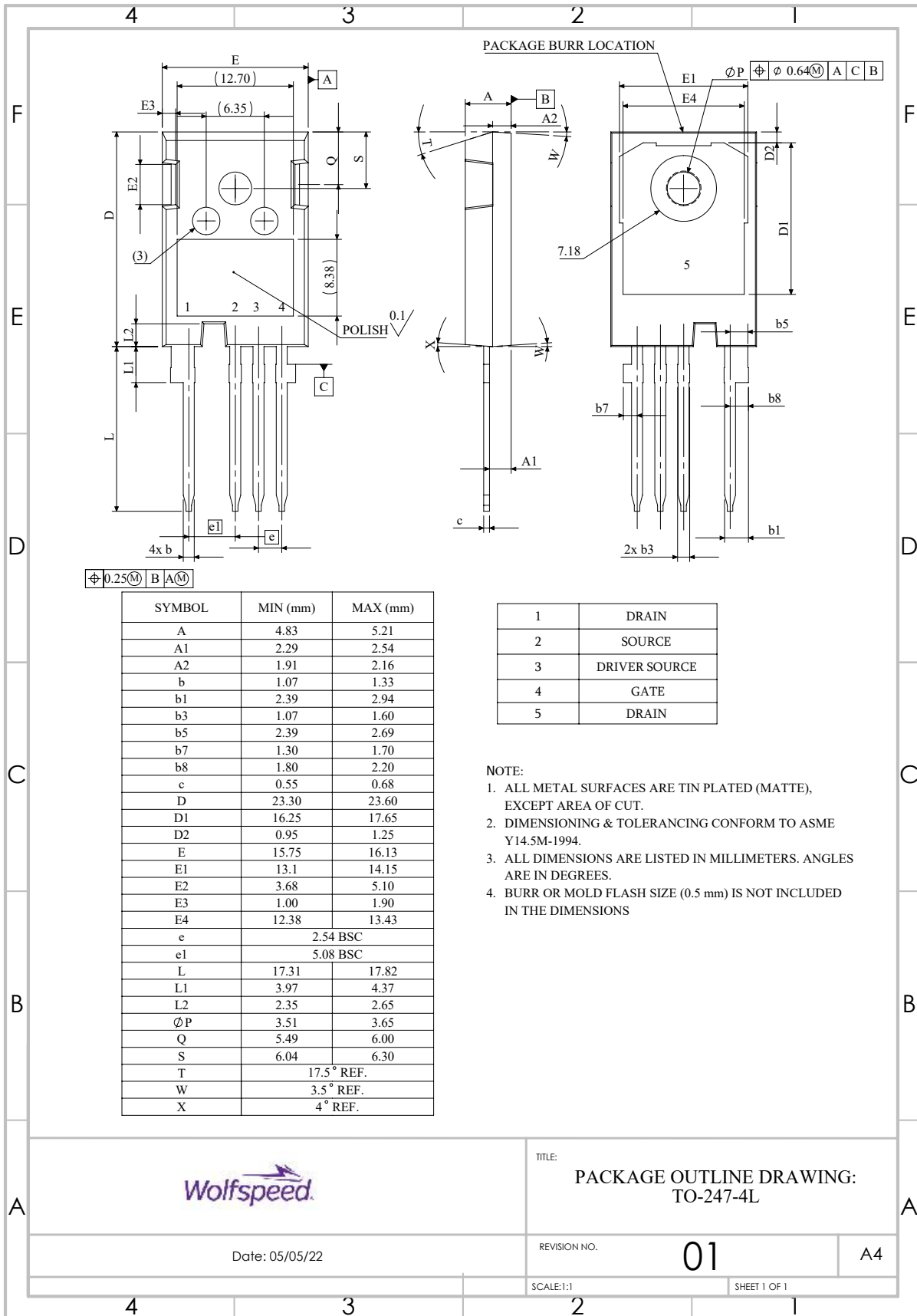


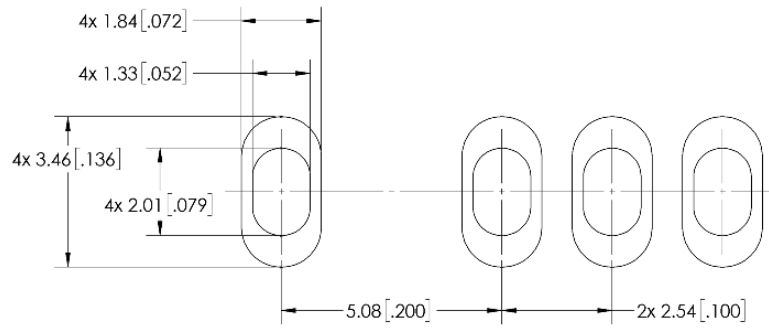
Figure 28. Body Diode Recovery Test Circuit

Package Dimensions





## Recommended Solder Pad Layout





## Revision history

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Document Version	Date of release	Description of changes
1.0	December-2020	Initial datasheet
2.0	October-2022	Wolfspeed Branding Package Outline and Solder Pad Layout Diagrams Updated VGS note added



## Notes & Disclaimer

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